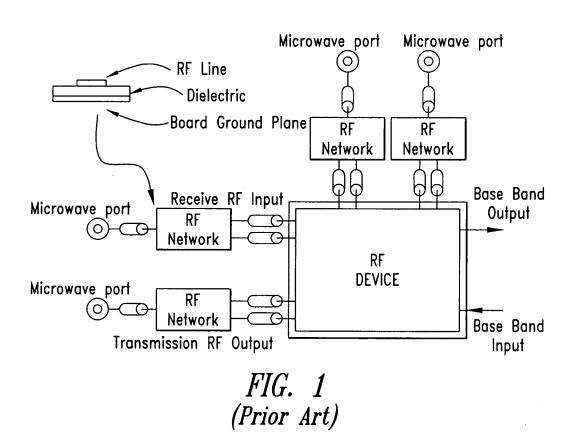
le: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS

Express Mail No. EV336594715US

"REPLACEMENT SHEET"

Filtry (s): Guiseppe Di Gregorio et al. Serial No. 10/033,364

Docket No. 856063.678



Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING COUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Serial No. 10/033,364 Docket No. 856063.678

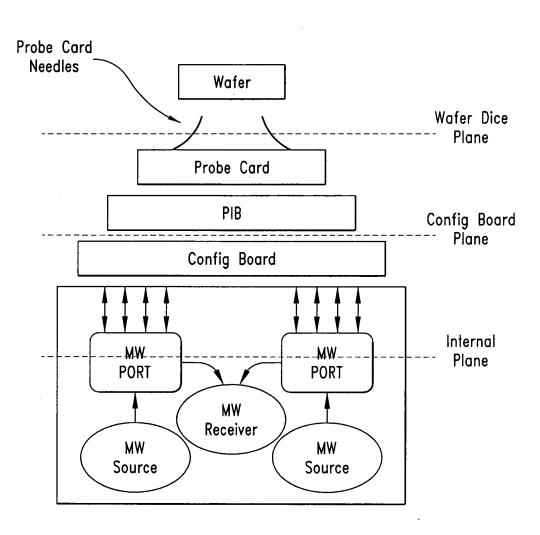


FIG. 2 (Prior Art)

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING

EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US

"REPLACEMENT SHEET"

Inventor(s): Guiseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

Section 1 $\begin{bmatrix} S_{11} & S_{12} \\ S_{21} & S_{22} \end{bmatrix}$

FIG. 3

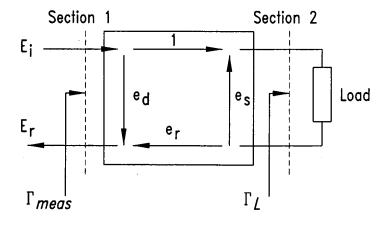


FIG. 4

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Guiseppe Di Gregorio et al. Serial No. 10/033,364 MAR 0 8 2004 %

Docket No. 856063.678

uwport 1 calibrate module Low Noise Port Ina .⊑ .⊑ ont out gain/ gain/ atten atten from from to uwsrc uwsrc 4 uw_mm uwsrc 1 uwsrc 1

FIG. 5



Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033.364 Docket No. 856063.678

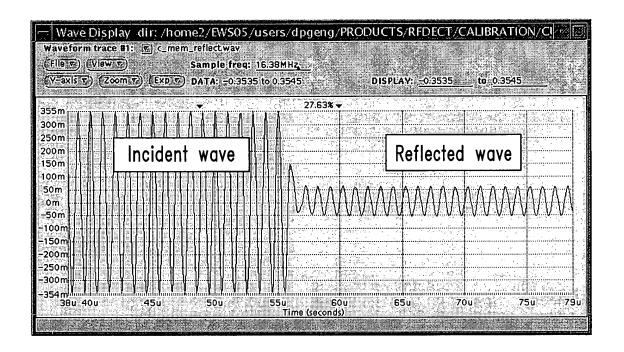


FIG. 6

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET" Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

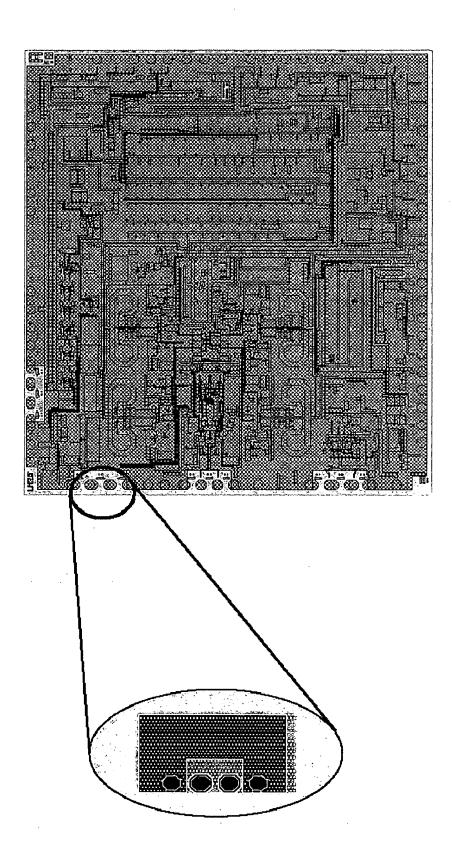


FIG. 7

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Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

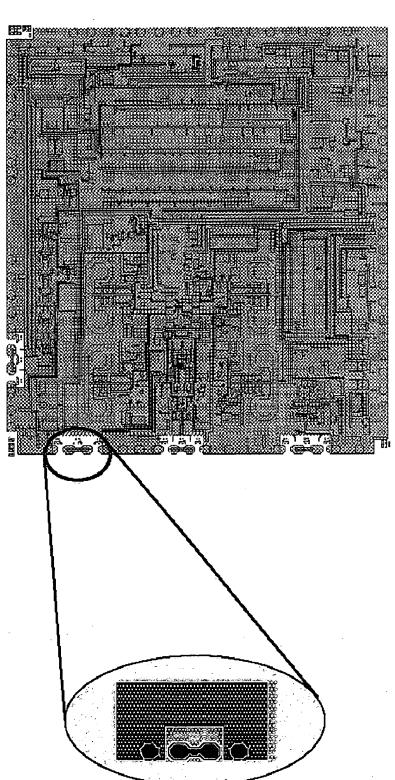
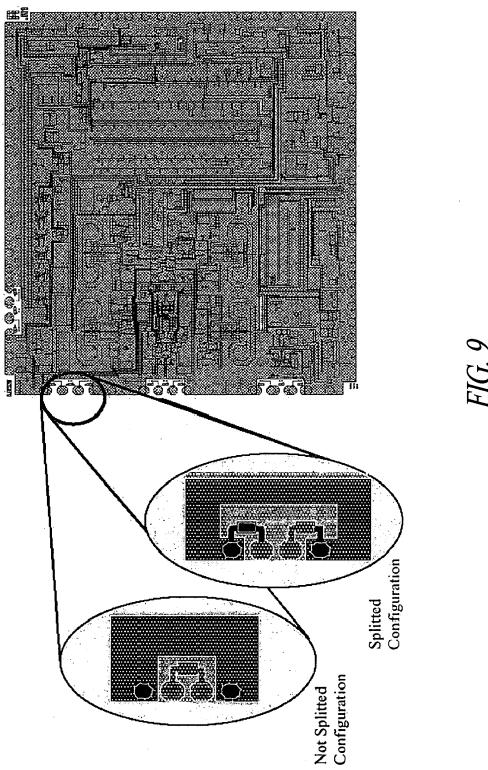


FIG. 8

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET" Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678



Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

FIG. 10

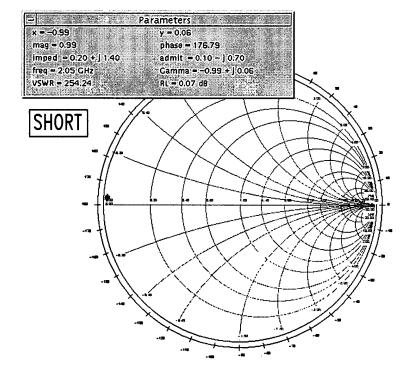


FIG. 11

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET" Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678



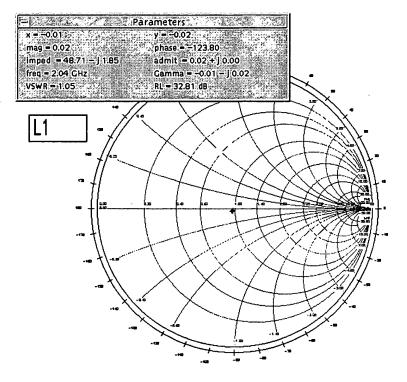


FIG. 12

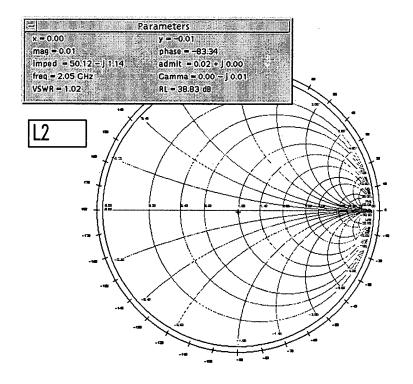


FIG. 13

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364

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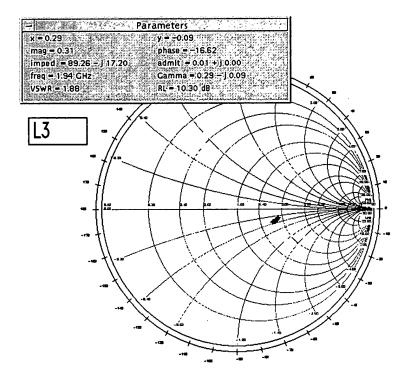


FIG. 14

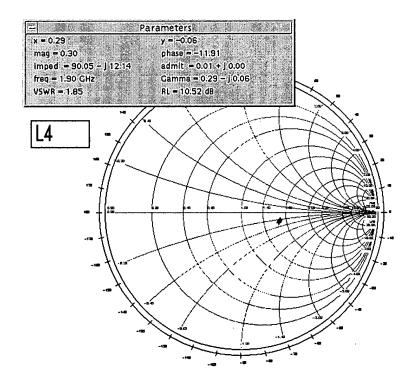


FIG. 15



Title: TEST BOARD DE-ÉMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

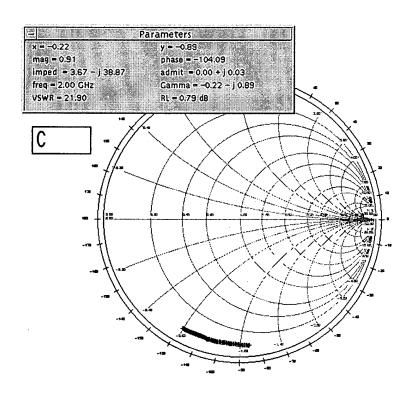


FIG. 16

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

No. 10/033,364 Docket No. 856063.678

nventor(s): Guiseppe Di Gregorio et al. Serial No. 10/033,364

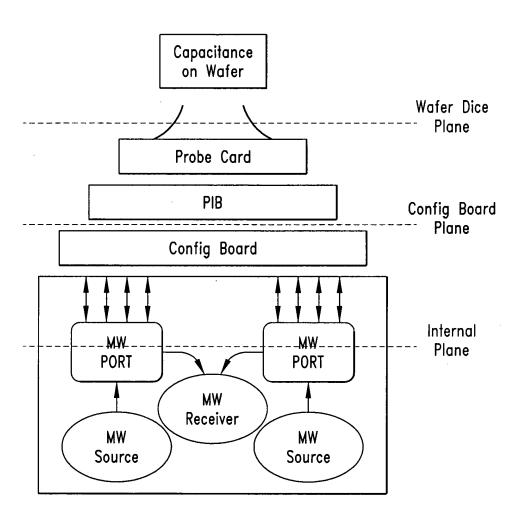


FIG. 17

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033. "REPLACEMENT SHEET" Docket No. 856063.678

Serial No. 10/033,364

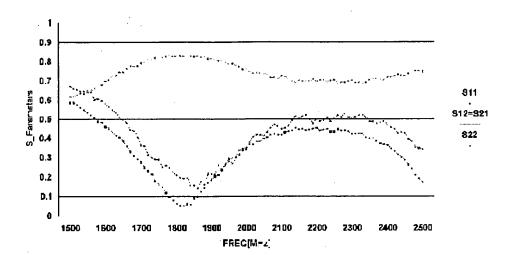


FIG. 18

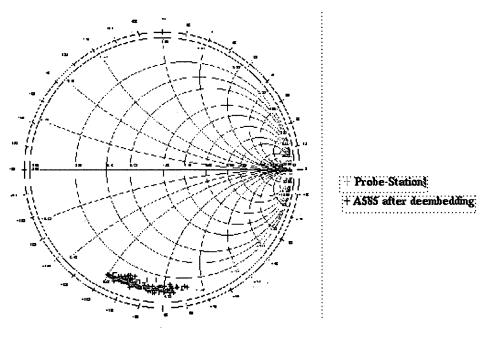
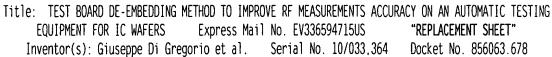


FIG. 19





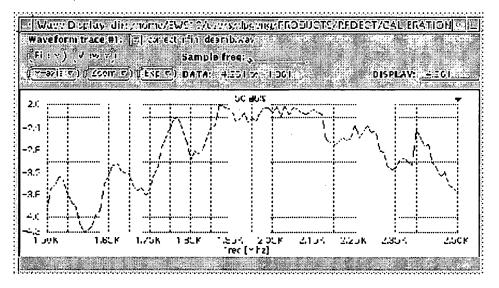


FIG. 20

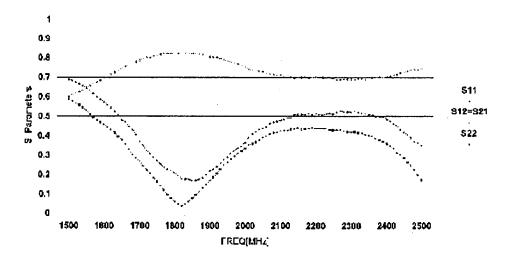
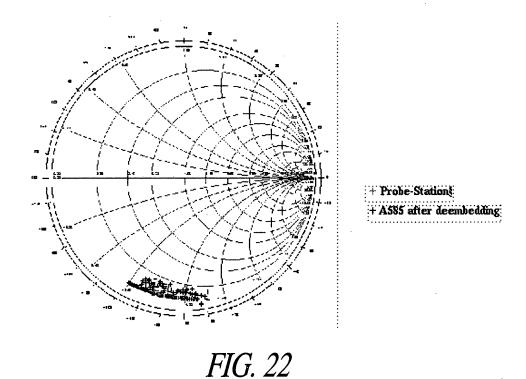


FIG. 21

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033.364 Docket No. 856063.678





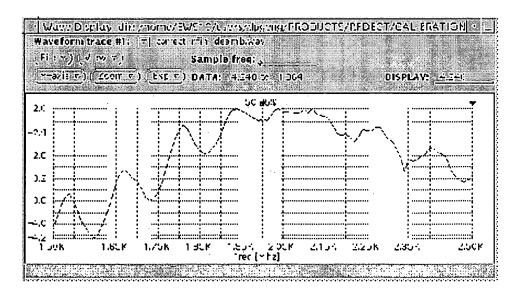


FIG. 23

Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364



Docket No. 856063.678

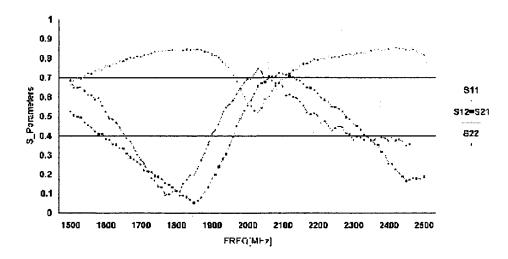


FIG. 24

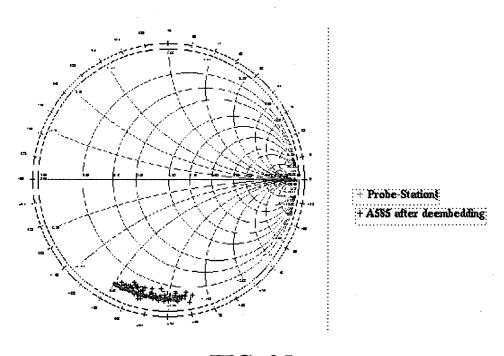


FIG. 25



Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364

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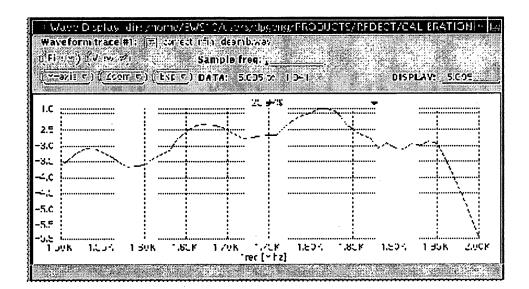


FIG. 26

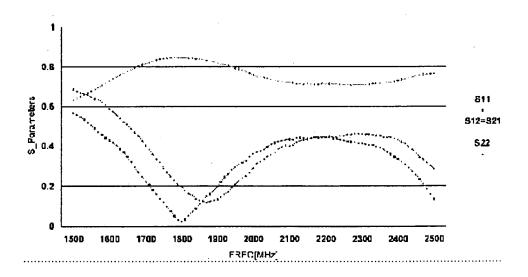


FIG. 27



Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"

Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

+ ASSS after deembedding

FIG. 28

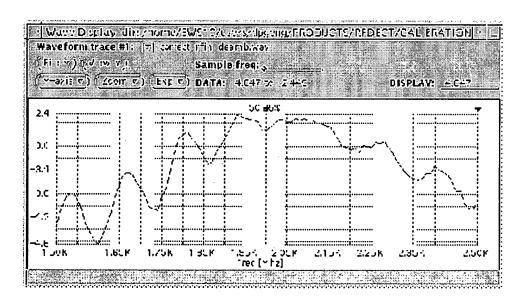


FIG. 29